



Liquid Chemicals Japan TC Chapter

Meeting Summary and Minutes

Japan Spring Meetings 2025
 Friday, May 16, 2025
 Room 1, SEMI Japan office / OVTCCM (Hybrid)
 3:00 pm - 5:00 pm JST

TC Chapter Announcements

Next TC Chapter Meeting

3:00 pm – 5:00 pm JST, September 4, 2025 @ SEMI Japan office and OVTCCM (Hybrid)

Table 1 Meeting Attendees

Italic indicates virtual participants

Co-Chairs: Yoshiyuki Fujitani (SCREEN Semiconductor Solutions Co., Ltd.) / Takuya Nagafuchi (Nihon Entegris G.K.)

SEMI Staff: Takeaki Hirabara (SEMI Japan)

<i>Company</i>	<i>Last</i>	<i>First</i>	<i>Company</i>	<i>Last</i>	<i>First</i>
<i>SCREEN Semiconductor Solutions Co., Ltd.</i>	<i>Fujitani</i>	<i>Yoshiyuki</i>	Particle Measuring Systems, Inc.	Takeshita	Mitsuyoshi
Nihon Entegris G.K.	Nagafuchi	Takuya	PILLAR Corporation	Nishi	Takashi
Pall Corporation	Nakagawa	Hisashi	Nippon Steel Stainless Steel Pipe Co., Ltd.	Miyahara	Osamu
CKD Corporation	Yasue	Hiroto	Tokyo Dylec	Yanagiuchi	Mamoru
CKD Corporation	Kokuryu	Yoshihiro	<i>Organo Corporation</i>	<i>Sugawara</i>	<i>Hiroshi</i>
RION CO., LTD.	Shimmura	Masaki	<i>Tokuyama Corporation</i>	<i>Tono</i>	<i>Seiji</i>
RION CO., LTD.	Kondo	Kaoru	<i>Organo Corporation</i>	<i>Futatsuki</i>	<i>Takashi</i>
AIST-National Institute of Advanced Industrial and Technology	Kato	Haruhisa	SEMI Japan	Kanno	Hirofumi
Advance Electric Co., Inc.	Sasao	Kimihito	SEMI Japan	Koga	Nahoko
Advance Electric Co., Inc.	Kaiya	Naoko	SEMI Japan	Hirabara	Takeaki

Table 2 Leadership Changes

<i>WG/TF/SC/TC Name</i>	<i>Previous Leader</i>	<i>New Leader</i>
None		

Table 3 TC Chapter Structure Changes

<i>Previous WG/TF/SC Name</i>	<i>New WG/TF/SC Name or Status Change</i>
None	

Table 4 Ballot Results

<i>Document #</i>	<i>Document Title</i>	<i>Committee Action</i>
7267	Revision to SEMI C77-0818, TEST METHOD FOR DETERMINING THE COUNTING EFFICIENCY OF LIQUID-BORNE PARTICLE COUNTERS FOR WHICH THE	Failed

Table 4 Ballot Results

<i>Document #</i>	<i>Document Title</i>	<i>Committee Action</i>
	MINIMUM DETECTABLE PARTICLE SIZE IS BETWEEN 30 nm AND 100 nm, with title change to: TEST METHOD FOR DETERMINING THE COUNTING EFFICIENCY OF LIQUID-BORNE PARTICLE COUNTERS FOR WHICH THE MINIMUM DETECTABLE PARTICLE SIZE IS IN THE RANGE OF 20 nm TO 100 nm	

#1 **Passed** ballots and line items will be submitted to the ISC Audit & Review Subcommittee for procedural review.

#2 **Failed** ballots and line items were returned to the originating task forces for re-work and re-balloting or abandoning.

Table 5 Ratification Ballot Results

<i>Document #</i>	<i>Document Title</i>	<i>ISC A&R Action</i>	<i>A&R Forms</i>
None			

Note 1: **Passed** Ratification ballots will be submitted to SEMI publication for final processing.

Note 2: **Failed** Ratification ballots were returned to the originating task forces for re-work and re-balloting or abandoning.

Table 6 Activities Approved by the GCS between meetings of the TC Chapter

<i>#</i>	<i>Type</i>	<i>SC/TF/WG</i>	<i>Details</i>
None			

Table 7 Authorized Activities

Listing of all revised or new SNARF(s) approved by the Originating TC Chapter.

<i>#</i>	<i>Type</i>	<i>SC/TF/WG</i>	<i>Details</i>
None			

#1 SNARFs and TFOFs are available for review on the SEMI Web site at:

<http://downloads.semi.org/web/wstdsbal.nsf/TFOFSNARE>

Table 8 Authorized Ballots

<i>#</i>	<i>When</i>	<i>TF</i>	<i>Details</i>
7267	Cycle 8 or later, 2025	Liquid-borne Particle Counter Task Force	Revision to SEMI C77-0818, TEST METHOD FOR DETERMINING THE COUNTING EFFICIENCY OF LIQUID-BORNE PARTICLE COUNTERS FOR WHICH THE MINIMUM DETECTABLE PARTICLE SIZE IS BETWEEN 30 nm AND 100 nm, with title change to: TEST METHOD FOR DETERMINING THE COUNTING EFFICIENCY OF LIQUID-BORNE PARTICLE COUNTERS FOR WHICH THE MINIMUM DETECTABLE PARTICLE SIZE IS IN THE RANGE OF 20 nm TO 100 nm
7255	Cycle 9 or later, 2025	Liquid Filter TF	Revision of SEMI C89-0116: Test Method for Measuring Particle Removal Performance of Liquid Filters Rated Below 30 nm by Inductively Coupled Plasma - Mass Spectrometry
7254	Cycle 9 or later, 2025	Liquid Filter TF	Revision of SEMI F110-0712: Test Method for Mono-Dispersed Polystyrene Latex (PSL) Challenge of Liquid Filters

Table 9 SNARF(s) Granted a One-Year Extension

<i>#</i>	<i>TF</i>	<i>Title</i>	<i>Expiration Date</i>
6911	Liquid Filter TF	New Standard, Test Method For Metal Removal Performance Of Liquid Filter	March 17, 2026



Table 10 SNARF(s) Abolished

#	TF	Title
None		

Table 11 Standard(s) to receive Inactive Status

Standard Designation	Title
None	

Table 12 New Action Items

Item #	Assigned to	Details
LC_20250516-1	SEMI Staff	Document list check issued by Liquid Chemicals Japan TC chapter.

Table 13 Previous Meeting Action Items

Item #	Assigned to	Details
None		

1 Welcome, Reminders, and Introductions

Takuya Nagafuchi (Nihon Entegris G.K.), called the meeting to order at 3:00 PM JST. The meeting reminders on antitrust issues, intellectual property issues and holding meetings with international attendance were reviewed. Attendees introduced themselves.

Attachment: 1. Required_Meeting_Element Dec 2024_JPupdated

2 Review of Previous Meeting Minutes

The TC Chapter reviewed the minutes of the previous meeting.

Motion: Approve the minutes as written.

By / 2nd: Yoshiyuki Fujitani (SCREEN Semiconductor Solutions Co., Ltd.) / Kimihito Sasao (Advance Electric Co., Inc.)

Discussion: None.

Vote: Result: 15-Y 0-N. **Motion Passed.**

Attachment: 2. Liquid Mins_241212 HK v1.0

3 Liaison Reports

3.1 JRSC

- Hirofumi Kanno (SEMI Japan) reported about career change of Sado san (a member of JRSC leaders) verbally.

3.2 GCS

- There was no reportable matter.

3.3 *Liquid Chemicals North America TC Chapter*

Takeaki Hirabara (SEMI Japan) reported for the Liquid Chemicals North America TC Chapter. Of notes:

- Last meeting
 - Winter
 - Day 1: Tuesday, February 25, 13:00-16:00 Pacific
 - Day 2: Wednesday, February 26, 13:00-16:00 (tentative)
 - SEMI HQ in Milpitas, CA
 - Spring
 - Tuesday, April 8, 13:00-15:00 Pacific
 - OVTCCM
- Next meeting (NA Summer Meeting)
 - Day 1: Tuesday, June 3, 13:00-16:00 Pacific
 - Day 2: Wednesday, June 4, 13:00-16:00 (tentative)
 - SEMI HQ in Milpitas, CA
- One Co-Chairs stepped back, and the Organization Chart will be updated.

Attachment: 3. NA LChem Liaison Report Feb2025 v1

3.4 *Liquid Chemicals Europe TC Chapter*

- There was no reportable matter due to no activity.

4 SEMI Staff Report

Takeaki Hirabara gave the SEMI Staff Report. Of notes:

- Introduction of 2025 calendar of SEMICON events.
- Announcement that postponement of enforcement of Connect@SEMI transition implementation

Attachment: 4. Staff Report Feb 2025 v2_ay

5 Ballot Review

5.1 Doc.# 7267, Revision to SEMI C77-0818, TEST METHOD FOR DETERMINING THE COUNTING EFFICIENCY OF LIQUID-BORNE PARTICLE COUNTERS FOR WHICH THE MINIMUM DETECTABLE PARTICLE SIZE IS BETWEEN 30 nm AND 100 nm, with title change to: TEST METHOD FOR DETERMINING THE COUNTING EFFICIENCY OF LIQUID-BORNE PARTICLE COUNTERS FOR WHICH THE MINIMUM DETECTABLE PARTICLE SIZE IS IN THE RANGE OF 20 nm TO 100 nm

→ This failed and will be back to TF for rework. Refer attachment for more details.

Attachment: 5. Ballot report with Technical Change_7267

6 Subcommittee and Task Force Reports

6.1 Liquid Filter Task Force

Hisashi Nakagawa (Pall Corporation) reported for the Liquid Filter Task Force. Of notes:

- Activity
 - #7255 Revision of SEMI C89-0116: Test Method for Measuring Particle Removal Performance of Liquid Filters Rated Below 30 nm by Inductively Coupled Plasma - Mass Spectrometry (ICP-MS)
 - 2025/9 Document for re-submission to be confirmed
 - 2025/2H or later Document submitted to ballot
 - #7254 Revision of SEMI F110-0712: Test Method for Mono-Dispersed Polystyrene Latex (PSL) Challenge of Liquid Filters
 - 2025/9 Document for re-submission to be confirmed
 - 2025/2H or later Document submitted to ballot
 - #6911 New Standard: Test Method for Metal Removal Performance of Liquid Filter
 - 2025/2H 1st Draft to be prepared followed by Draft review

Attachment: 6. LF-TF Meeting Minutes_20250516

6.2 Liquid-Borne Particle Counter Task Force

Masaki Shimmura (RION CO., LTD.) reported for the Liquid Borne Particle Counter Task Force. Of notes:

- Activity
 - Rework for #7267 TEST METHOD FOR DETERMINING THE COUNTING EFFICIENCY OF LIQUIDBORNE PARTICLE COUNTERS FOR WHICH THE MINIMUM DETECTABLE PARTICLE SIZE IS BETWEEN 30 NM AND 100 NM.

Attachment: 7. 20250516_SEMI LC TC LPC TF Activity Report

6.3 Trace Metal Analysis for High Pure IPA Task Force

Hiroshi Sugawara (Organo Corporation) reported for the Trace Metal Analysis for High Pure IPA Task Force. Refer details on the attachment.

Attachment: 8. IPA-TF Report_20250516

6.4 Valve & Fitting Task Force

Kimihito Sasao (Advance Electric Co., Inc.) reported for the Valve & Fitting Task Force. Of notes:

- Activity
 - Review of the abolition and invalidation of existing standards

Attachment: 9. V&F Meeting Minutes_20250516

7 Old Business

7.1 Project Period Review –

7.1.1 # 6911: New Standard, Test Method For Metal Removal Performance Of Liquid Filter



Motion: Approve a 1 year extension of the project period for the SNARF
By / 2nd: Hisashi Nakagawa (Pall Corporation)/
Kimihiro Sasao (Advance Electric Co., Inc.)
Discussion: None
Vote: Result: 13-Y 0-N Voting Result: Pass - 100.00%. Voting Rule: Majority

7.2 5 Year Review Check - None

8 New Business

8.1 3 Ballot Submissions

- Ballot - Cycle 8 or later, 2025: 7267 / Revision to SEMI C77-0818, TEST METHOD FOR DETERMINING THE COUNTING EFFICIENCY OF LIQUID-BORNE PARTICLE COUNTERS FOR WHICH THE MINIMUM DETECTABLE PARTICLE SIZE IS BETWEEN 30 nm AND 100 nm, with title change to: TEST METHOD FOR DETERMINING THE COUNTING EFFICIENCY OF LIQUID-BORNE PARTICLE COUNTERS FOR WHICH THE MINIMUM DETECTABLE PARTICLE SIZE IS IN THE RANGE OF 20 nm TO 100 nm
Motion: Authorize the Document for Letter Ballot
By / 2nd: Masaki Shimmura (RION CO., LTD.)/
Mitsuyoshi Takeshita (Particle Measuring Systems, Inc.)
Discussion: None
Vote: Result: 12-Y 0-N Voting Result: Pass - 100.00%. Voting Rule: Majority
- Ballot - Cycle 9 or later, 2025: 7255 / Revision of SEMI C89-0116: Test Method for Measuring Particle Removal Performance of Liquid Filters Rated Below 30 nm by Inductively Coupled Plasma - Mass Spectrometry
Motion: Authorize the Document for Letter Ballot
By / 2nd: Hisashi Nakagawa (Pall Corporation)/
Mitsuyoshi Takeshita (Particle Measuring Systems, Inc.)
Discussion: None
Vote: Result: 12-Y 0-N Voting Result: Pass - 100.00%. Voting Rule: Majority
- Ballot - Cycle 9 or later, 2025: 7254 / Revision of SEMI F110-0712: Test Method for Mono-Dispersed Polystyrene Latex (PSL) Challenge of Liquid Filters
Motion: Authorize the Document for Letter Ballot
By / 2nd: Hisashi Nakagawa (Pall Corporation)/
Mitsuyoshi Takeshita (Particle Measuring Systems, Inc.)
Discussion: None
Vote: Result: 13-Y 0-N Voting Result: Pass - 100.00%. Voting Rule: Majority

9 Action Item Review

9.1 Open Action Items



<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
None		

9.2 Open Action Items

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
LC_20250516-1	SEMI Staff	Document list check issued by Liquid Chemicals Japan TC chapter.

10 Next Meeting and Adjournment

The next meeting is scheduled for Thursday, September 4, 2025, 3:00 pm - 5:00 pm JST at SEMI Japan office via Official Virtual TC Chapter Meeting. Refer to <http://www.semi.org/standards> for the current list of events.

Adjournment: 5:00pm

Respectfully submitted by:

Takeaki Hirabara
Standards & EHS
SEMI Japan
Email: thirabara@semi.org

Minutes tentatively approved by:

Yoshiyuki Fujitani (SCREEN Semiconductor Solutions Co., Ltd.)	June 10, 2025
Takuya Nagafuchi (Nihon Entegris G.K.)	June 4, 2025

Table 14 Index of Available Attachments#1

<i>Title</i>	<i>Title</i>
1. Required_Meeting_Element Dec 2024_JPupdated	2. Liquid Mins_241212 HK v1.0
3. NA LChem Liaison Report Feb2025 v1	4. Staff Report Feb 2025 v2 ay
5. Ballot report with Technical Change 7267	6. LF-TF Meeting Minutes 20250516
7. 20250516 SEMI LC TC LPC TF Activity Report	8. IPA-TF Report 20250516
9. V&F Meeting Minutes 20250516	

Due to file size and delivery issues, attachments must be downloaded separately. A .zip file containing all attachments for these minutes is available at www.semi.org. For additional information or to obtain individual attachments, please contact Takeaki Hirabara at the contact information above